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, "Front Matter: Volume 11035," Proc. SPIE 11035, Optics Damage and Materials Processing by EUV/X-ray Radiation VII, 1103501 (9 July 2019); doi: 10.1117/12.2535651

Event: SPIE Optics + Optoelectronics, 2019, Prague, Czech Republic

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Optics Damage and Materials Processing by EUV/X-ray Radiation VII

**Libor Juha
Saša Bajt
Stéphane Guizard**
Editors

**1–3 April 2019
Prague, Czech Republic**

Sponsored and Published by
SPIE

Volume 11035

Proceedings of SPIE 0277-786X, V. 11035

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Optics Damage and Materials Processing by EUV/X-ray Radiation VII, edited by Libor Juha, Saša Bajt, Stéphane Guizard,
Proc. of SPIE Vol. 11035, 1103501 · © 2019 SPIE · CCC code: 0277-786X/19/\$18 · doi: 10.1117/12.2535651

Proc. of SPIE Vol. 11035 1103501-1

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Author(s), "Title of Paper," in *Optics Damage and Materials Processing by EUV/X-ray Radiation VII*, edited by Libor Juha, Saša Bajt, Stéphane Guizard, Proceedings of SPIE Vol. 11035 (SPIE, Bellingham, WA, 2019) Seven-digit Article CID Number.

ISSN: 0277-786X
ISSN: 1996-756X (electronic)

ISBN: 9781510627369
ISBN: 9781510627376 (electronic)

Published by
SPIE
P.O. Box 10, Bellingham, Washington 98227-0010 USA
Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445
SPIE.org
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